Notice of References Cited Application/Control No. 10/798,009 Applicant(s)/Patent Under Reexamination GARRATT ET AL. Examiner John J. Zimmerman Art Unit Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,061,327	10-1991	Denzer et al.	148/693
*	В	US-5,194,102	03-1993	Wyss, Rebecca K.	148/695
¥	С	US-5,826,456	10-1998	Kawazoe et al.	72/253.1
¥	D	US-5,863,359	01-1999	Karabin et al.	148/437
*	E	US-6,231,995	05-2001	Yamashita et al.	428/598
*	F	US-6,325,869	12-2001	Liu et al.	148/439
×	G	US-2001/0020501	09-2001	Liu et al.	148/690
*	Н	US-2002/0014287	02-2002	YOSHIHARA et al.	148/417
*	ı	US-2002/0043640	04-2002	Takemoto et al.	251/368
*	J	US-2003/0008165	01-2003	Kawai et al.	428/586
*	К	US-522,736	07-1894	Name not available	52/729.2
*	L	US-4,294,625	10-1981	Hyatt et al.	148/550
*	М	US-4,336,075	06-1982	Quist et al.	148/550

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	σ					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	Х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No. 10/798,009	Applicant(s)/Patent Under Reexamination GARRATT ET AL.		
Examiner	Art Unit		
John J. Zimmerman	1775	Page 2 of 2	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,071,492	12-1991	Parker et al.	148/517
*	В	US-Reissue 34008	07-1992	Quist et al.	148/2
*	С	US-5,221,377	06-1993	Hunt et al.	148/417
*	D	US-5,759,302	06-1998	Nakai et al.	148/415
*	Ε	US-5,865,911	02-1999	Miyasato et al.	148/439
*	F	US-5,865,914	02-1999	Karabin et al.	148/693
*	G	US-5,980,206	11-1999	Hunter et al.	416/134A
*	Н	US-6,113,711	09-2000	Armanie et al.	148/689
*	-	US-6,277,219	08-2001	Heinz et al.	148/552
*	٦	US-2002/0000492	01-2002	Schmidt, Hans-Juergen	244/125
*	К	US-6,364,250	04-2002	Brinck et al.	244/119
Ж	L	US-6,444,058	09-2002	Liu et al.	148/439
*	М	US-2002/0150498	10-2002	Chakrabarti et al.	420/532

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	Ν	11-071624	03-1999	Japan	Yamashita	
*	0	04-022508	01-1992	Japan		
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	TOTAL POSSIBLITY				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	K.R. Van Horn, "Factors Affecting Directional Properties in Aluminum Wrought Products", pp. 38-76, TRANSACTIONS OF THE ASM, Vol. 47, presented at the 36th Annual Convention of the Society, Chicago, II, November 3, 1954.			
*	V	H.Y. Hunsicker, "New Graphic Method for Analysis of Hot Deformation and Effects on Directional Properties", pp. 29-42, TRANSACTIONS OF THE METALLURGICAL SOCIETY OF AIME, Vol. 245, January 1969.			
*	w	P.I. Welch et al., "The Effect of Texture on Fatigue Crack Propagation in Aluminum Alloy 7075", pp. 332-335, ALUMINUM, 61 Jahrg 1985.			
¥	х	D.L. Chen et al., "Fatigue Crack Growth Behavior of X2095 Al-Li Alloy", pp. 1079-1086, International Journal of Fatigue 21, 1999.			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.